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Application/Control No.	Applicant(s)/Patent under Reexamination
10/643,063	CHOI ET AL.
Examiner	Art Unit
Dung Nguyen	2871

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SEARCHED			
Class	Subclass	Date	Examiner
349	42-43	5/28/2007	. DN
349	139	5/28/2007	DN
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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